



STFW6N120K3 STP6N120K3, STW6N120K3

N-channel 1200 V, 1.95 Ω , 6 A, TO-3PF, TO-220, TO-247
Zener-protected SuperMESHTM Power MOSFET

Features

| Type | V _{DSS} | R _{DS(on)} max | I _D | P _w |
|-------------|------------------|-------------------------|----------------|----------------|
| STFW6N120K3 | 1200 V | < 2.4 Ω | 6 A | 63 |
| STP6N120K3 | 1200 V | < 2.4 Ω | 6 A | 150 W |
| STW6N120K3 | 1200 V | < 2.4 Ω | 6 A | 150 W |

- 100% avalanche tested
- Extremely large avalanche performance
- Gate charge minimized
- Very low intrinsic capacitances
- Zener-protected

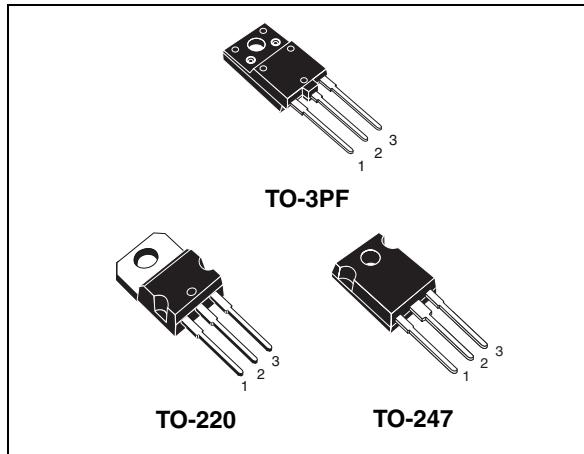


Figure 1. Internal schematic diagram

Application

- Switching applications

Description

These devices are an N-channel SuperMESHTM Power MOSFET obtained through optimization of ST's well-established strip-based PowerMESHTM layout. In addition to pushing on-resistance significantly down, special attention has been taken to ensure a very good dynamic performance coupled with a very large avalanche capability for the most demanding application.

Table 1. Device summary

| Order codes | Marking | Package | Packaging |
|-------------|---------|---------|-----------|
| STFW6N120K3 | 6N120K3 | TO-3PF | Tube |
| STP6N120K3 | | TO-220 | |
| STW6N120K3 | | TO-247 | |

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | | | Unit |
|----------------|--|------------|--------|--------|------|
| | | TO-3PF | TO-220 | TO-247 | |
| V_{GS} | Gate- source voltage | 30 | | | V |
| I_D | Drain current (continuous) at $T_C = 25^\circ\text{C}$ | 6 | | | A |
| I_D | Drain current (continuous) at $T_C = 100^\circ\text{C}$ | 3.8 | | | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 20 | | | A |
| P_{TOT} | Power dissipation at $T_C = 25^\circ\text{C}$ | 63 | 150 | 150 | W |
| I_{AR} | Max current during repetitive or single pulse avalanche (pulse width limited by T_{JMAX}) | 7 | | | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$) | 180 | | | mJ |
| $V_{ESD(G-S)}$ | G-S ESD (HBM-C = 100 pF, R = 1.5 kΩ) | 6000 | | | V |
| V_{ISO} | Insulation withstand voltage (AC) | 3500 | - | - | V |
| T_{stg} | Storage temperature | -55 to 150 | | | °C |
| T_J | Operating junction temperature | | | | |

1. Pulse width limited by safe operating area

Table 3. Thermal data

| Symbol | Parameter | TO-3PF | TO-220 | TO-247 | Unit |
|----------------|--|--------|--------|--------|------|
| $R_{thj-case}$ | Thermal resistance junction-case | 1.98 | 0.83 | | °C/W |
| $R_{thj-pcb}$ | Thermal resistance junction to pcb minimum footprint | - | - | - | °C/W |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max | 50 | 62.5 | 50 | °C/W |
| T_J | Maximum lead temperature for soldering purpose | 300 | | | °C |

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 4. On / off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|--|---|------|------|----------|--------------------------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source breakdown voltage | $I_D = 1 \text{ mA}, V_{GS} = 0$ | 1200 | - | - | V |
| I_{DSS} | Zero gate voltage drain current ($V_{GS} = 0$) | $V_{DS} = \text{Max rating}$ $V_{DS} = \text{Max rating}, T_J = 125^\circ\text{C}$ | - | - | 1 50 | μA μA |
| I_{GSS} | Gate-body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$ | - | - | ± 10 | μA |
| $V_{GS(\text{th})}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 100 \mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(\text{on})}$ | Static drain-source on resistance | $V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$ | - | 1.95 | 2.4 | Ω |

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------------------|---------------------------------------|--|------|-----------------|------|----------|
| C_{iss} | Input capacitance | | | | | pF |
| C_{oss} | Output capacitance | | | | | pF |
| C_{rss} | Reverse transfer capacitance | $V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$ | - | 1050 90 1 | - | pF |
| $C_{o(\text{tr})}^{(1)}$ | Equivalent capacitance time related | $V_{GS} = 0, V_{DS} = 0 \text{ to } 960 \text{ V}$ | - | 40 | - | pF |
| $C_{o(er)}^{(2)}$ | Equivalent capacitance energy related | $V_{GS} = 0, V_{DS} = 0 \text{ to } 960 \text{ V}$ | - | 25 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1 \text{ MHz open drain}$ | - | 3 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 960 \text{ V}, I_D = 7.2 \text{ A}, V_{GS} = 10 \text{ V}$ | | 34 | | nC |
| Q_{gs} | Gate-source charge | | - | 7 | - | nC |
| Q_{gd} | Gate-drain charge | (see Figure 20) | | 23 | | nC |

1. C_{oss} eq. time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .
2. C_{oss} eq. energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 6. Switching times on/off

| Symbol | Parameter | Test conditions | Min. | Typ. | Max | Unit |
|--------------|---------------------|--|------|------|-----|------|
| $t_{d(on)}$ | Turn-on delay time | | | 30 | | ns |
| t_r | Rise time | | | 12 | - | ns |
| $t_{d(off)}$ | Turn-off-delay time | $V_{DD} = 600 \text{ V}$, $I_D = 3.6 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see Figure 19) | - | 58 | - | ns |
| t_f | Fall time | | | 32 | | ns |

Table 7. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | - | 6 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | | | 20 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 5 \text{ A}$, $V_{GS} = 0$ | - | -- | 1.6 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 7.2 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$ | | 580 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 60 \text{ V}$, $T_J = 25 \text{ }^\circ\text{C}$ (see Figure 24) | - | 7 | - | μC |
| I_{RRM} | Reverse recovery current | | | 25 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 7.2 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$ | | 840 | | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 60 \text{ V}$, $T_J = 150 \text{ }^\circ\text{C}$ | - | 9 | - | μC |
| I_{RRM} | Reverse recovery current | (see Figure 24) | | 22 | | A |

1. Pulse width limited by safe operating area.
2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5%

Table 8. Gate-source Zener diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|------------|-------------------------------|--|------|------|------|------|
| BV_{GSO} | Gate-source breakdown voltage | $I_{GS} = \pm 1 \text{ mA}$ (open drain) | 30 | - | - | V |

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-3PF

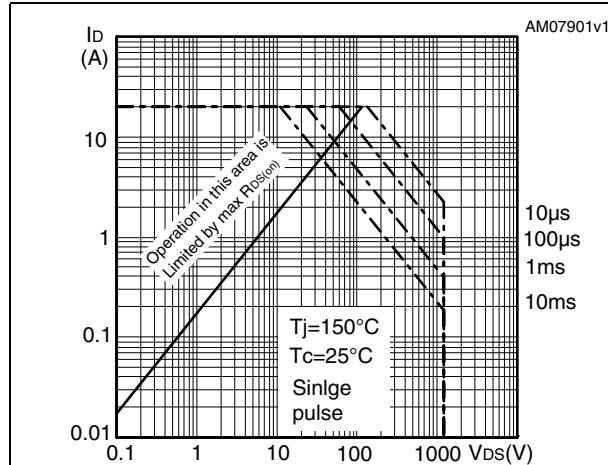


Figure 3. Thermal impedance for TO-3PF

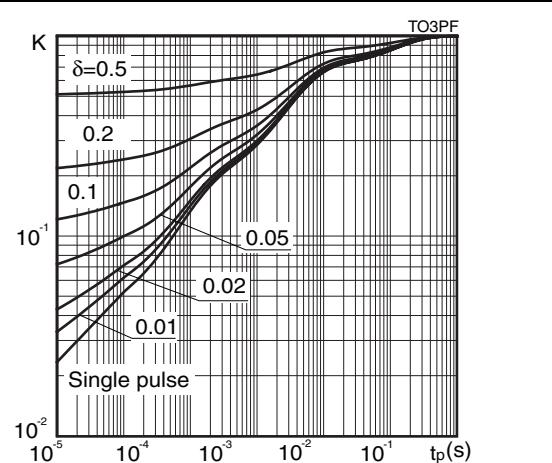


Figure 4. Safe operating area for TO-220

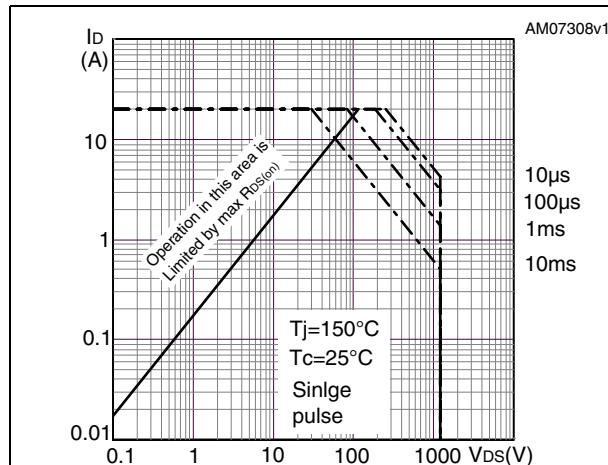


Figure 5. Thermal impedance for TO-220

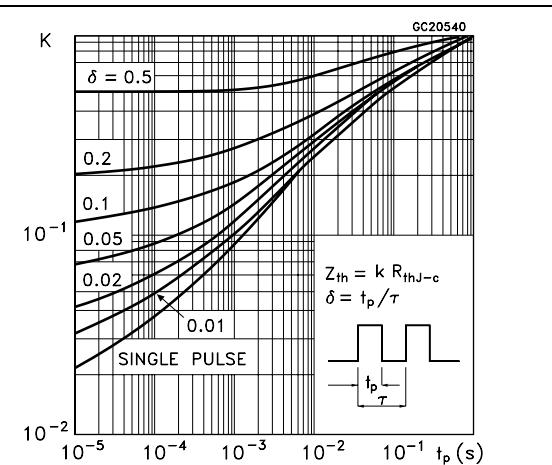


Figure 6. Safe operating area for TO-247

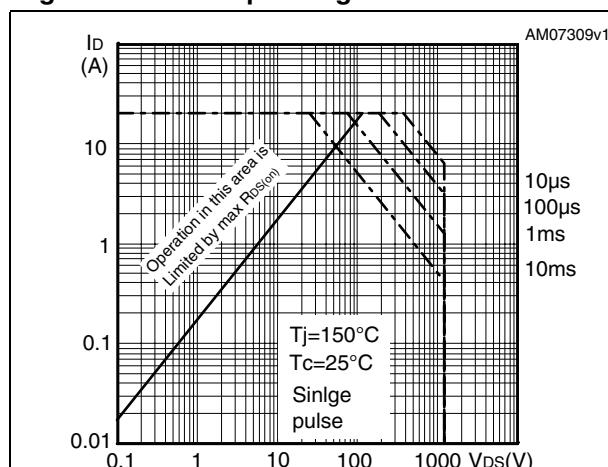


Figure 7. Thermal impedance for TO-247

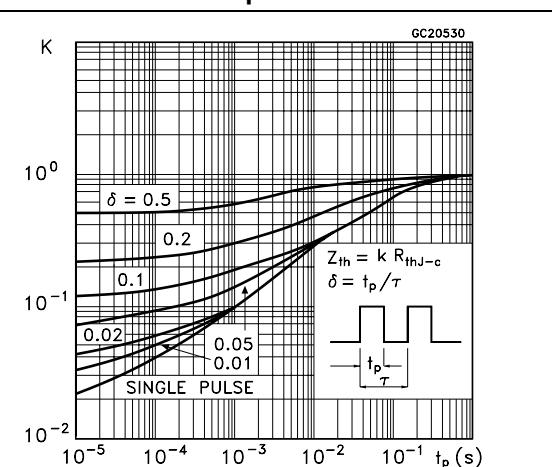


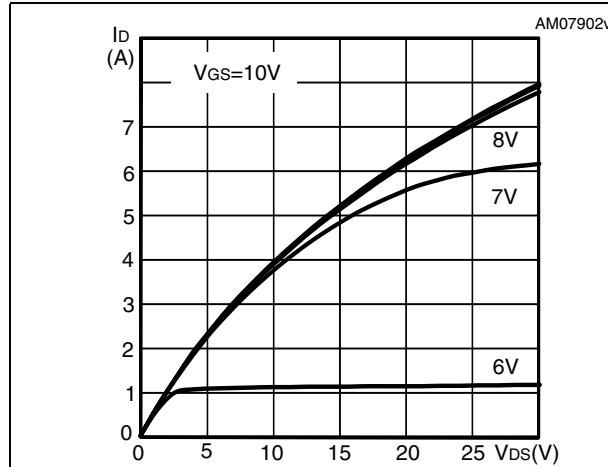
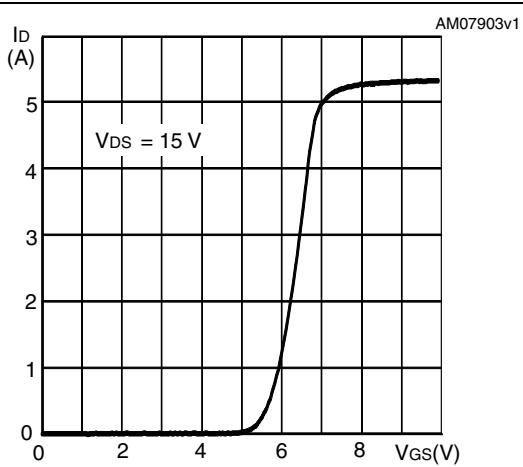
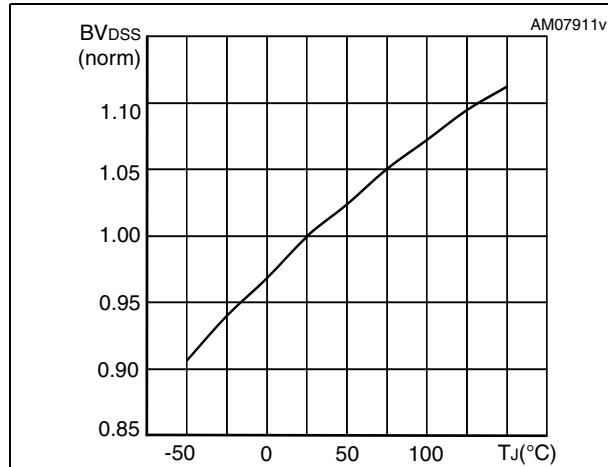
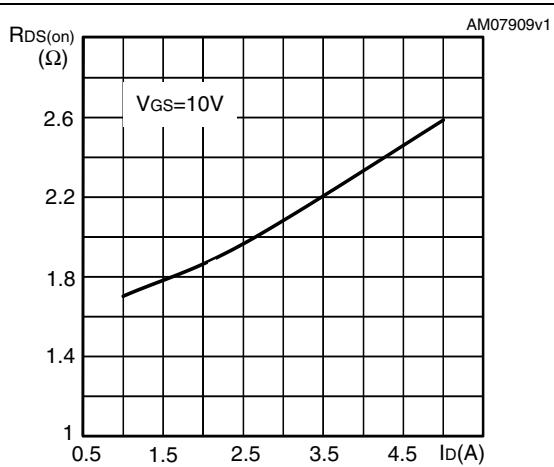
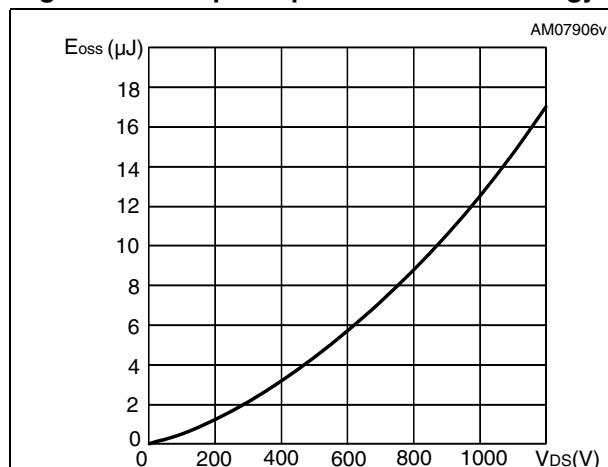
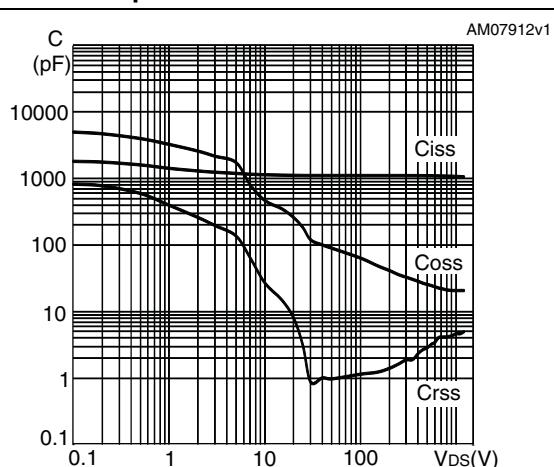
Figure 8. Output characteristics**Figure 9. Transfer characteristics****Figure 10. Normalized BV_{DSS} vs temperature****Figure 11. Static drain-source on resistance****Figure 12. Output capacitance stored energy****Figure 13. Capacitance variations**

Figure 14. Gate charge vs gate-source voltage **Figure 15. Normalized on resistance vs temperature**

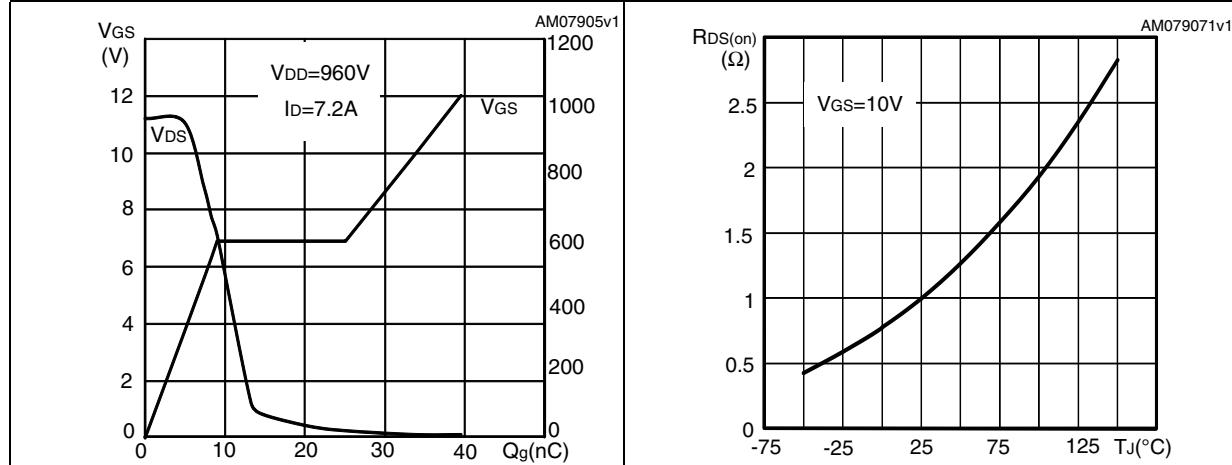


Figure 16. Normalized gate threshold voltage vs temperature **Figure 17. Maximum avalanche energy vs temperature**

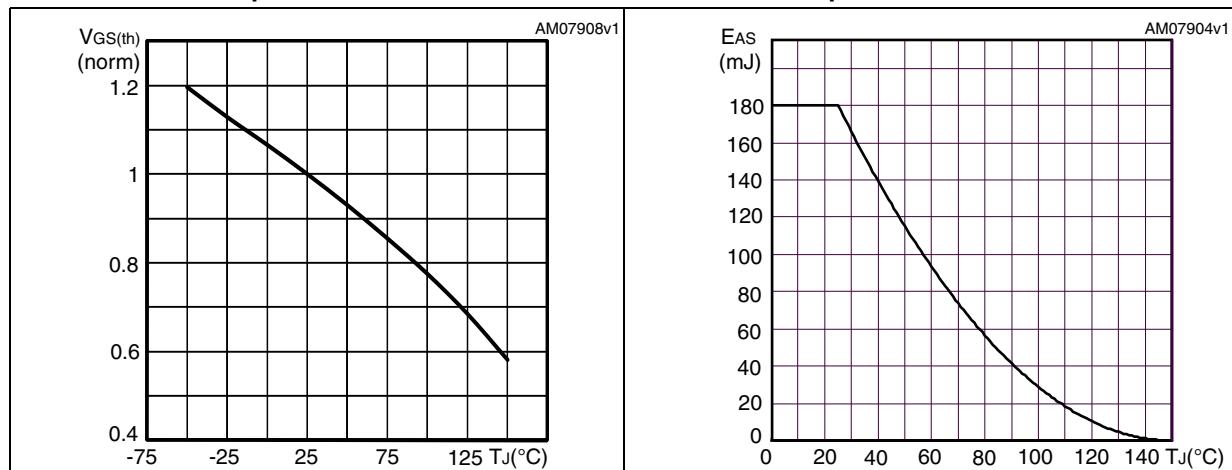
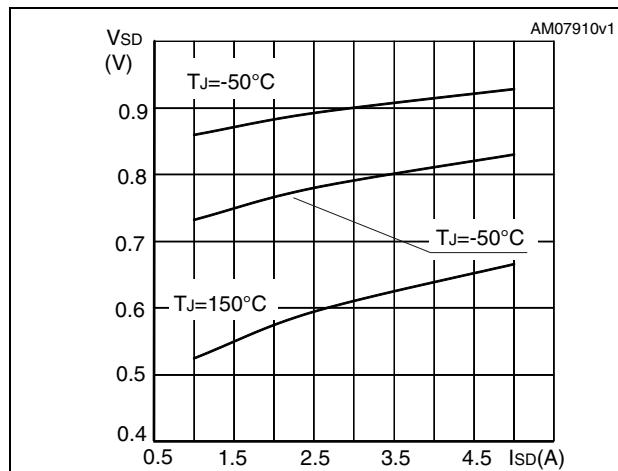


Figure 18. Source-drain diode forward characteristics



3 Test circuits

Figure 19. Switching times test circuit for resistive load

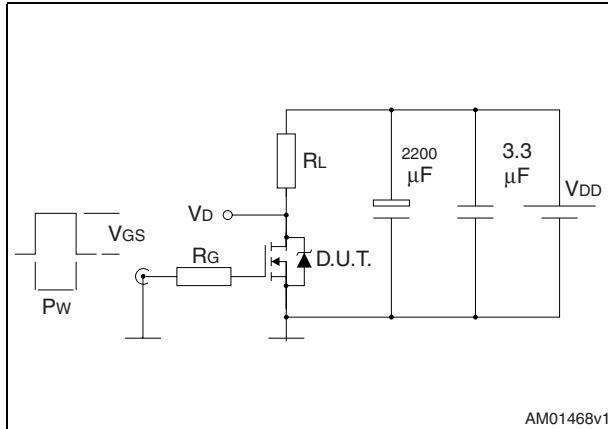


Figure 20. Gate charge test circuit

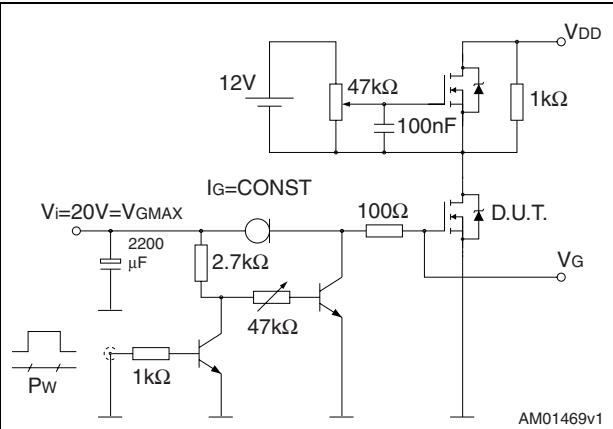


Figure 21. Test circuit for inductive load switching and diode recovery times

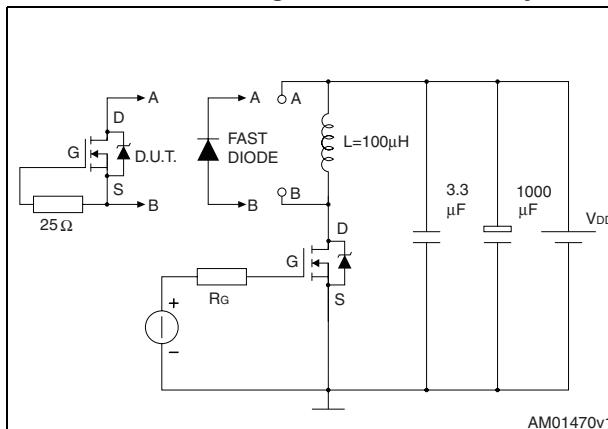


Figure 22. Unclamped inductive load test circuit

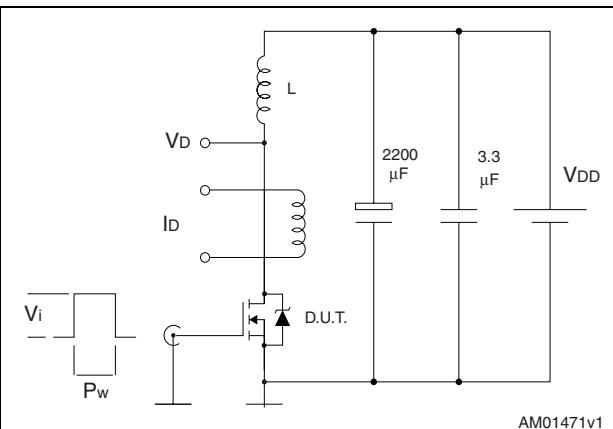


Figure 23. Unclamped inductive waveform

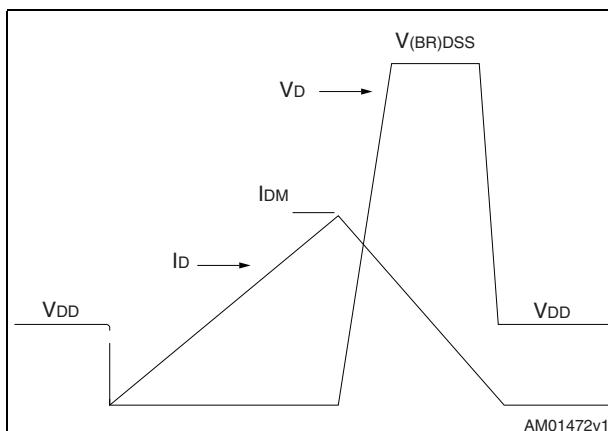
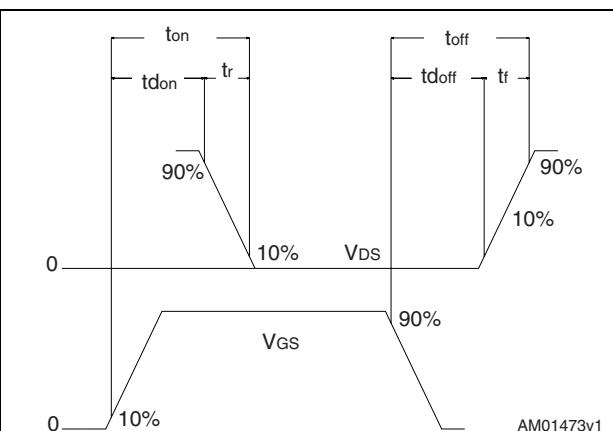


Figure 24. Switching time waveform

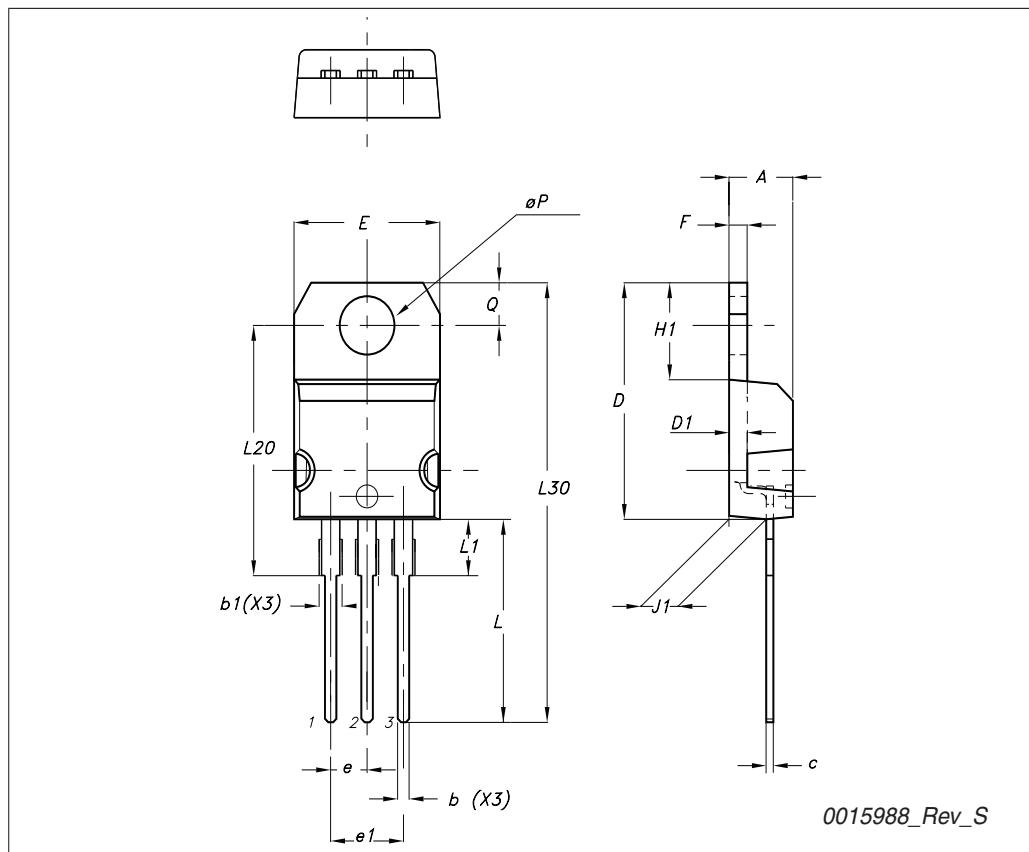


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

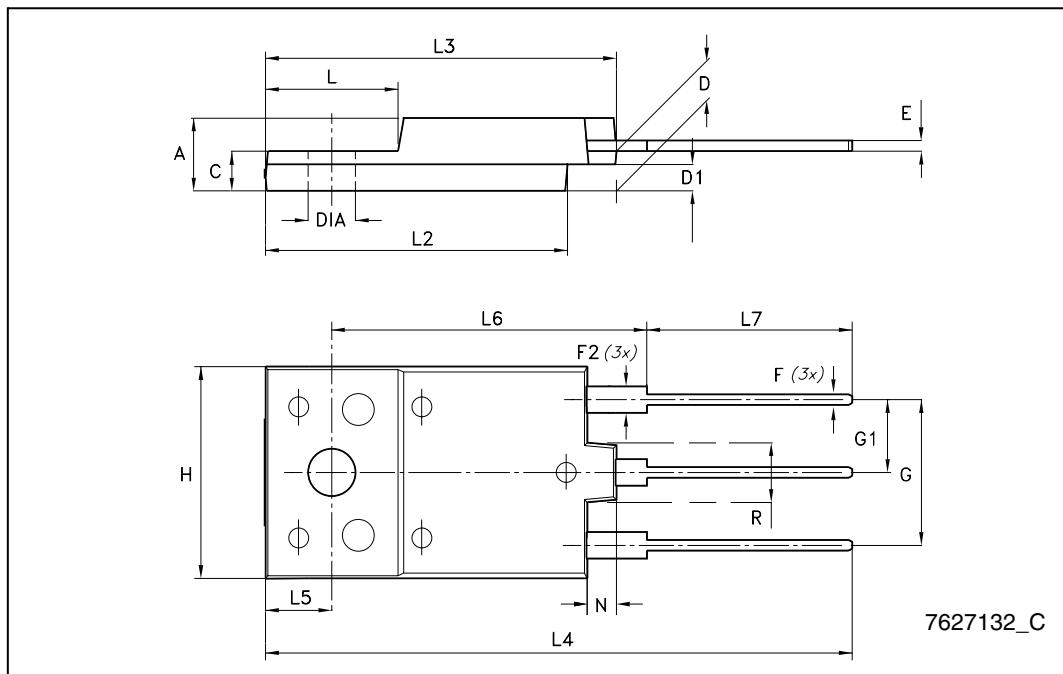
TO-220 type A mechanical data

| Dim | mm | | |
|---------------|-------|-------|-------|
| | Min | Typ | Max |
| A | 4.40 | | 4.60 |
| b | 0.61 | | 0.88 |
| b1 | 1.14 | | 1.70 |
| c | 0.48 | | 0.70 |
| D | 15.25 | | 15.75 |
| D1 | | 1.27 | |
| E | 10 | | 10.40 |
| e | 2.40 | | 2.70 |
| e1 | 4.95 | | 5.15 |
| F | 1.23 | | 1.32 |
| H1 | 6.20 | | 6.60 |
| J1 | 2.40 | | 2.72 |
| L | 13 | | 14 |
| L1 | 3.50 | | 3.93 |
| L20 | | 16.40 | |
| L30 | | 28.90 | |
| $\emptyset P$ | 3.75 | | 3.85 |
| Q | 2.65 | | 2.95 |



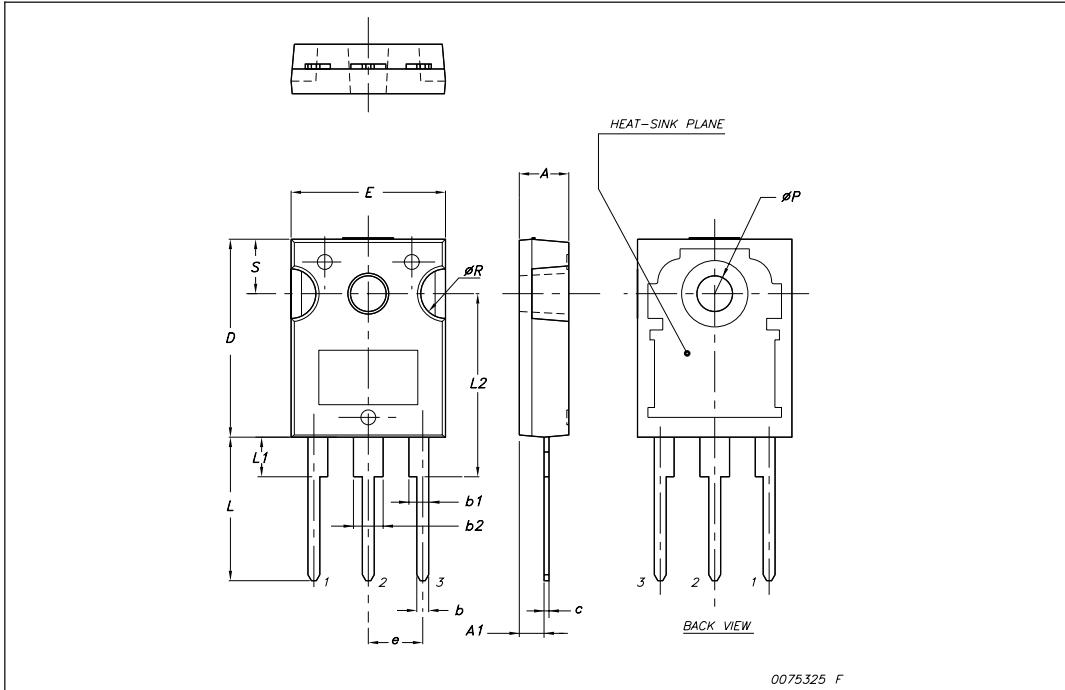
TO-3PF mechanical data

| DIM. | mm. | | |
|------|-------|------|-------|
| | min. | typ | max. |
| A | 5.30 | | 5.70 |
| C | 2.80 | | 3.20 |
| D | 3.10 | | 3.50 |
| D1 | 1.80 | | 2.20 |
| E | 0.80 | | 1.10 |
| F | 0.65 | | 0.95 |
| F2 | 1.80 | | 2.20 |
| G | 10.30 | | 11.50 |
| G1 | | 5.45 | |
| H | 15.30 | | 15.70 |
| L | 9.80 | 10 | 10.20 |
| L2 | 22.80 | | 23.20 |
| L3 | 26.30 | | 26.70 |
| L4 | 43.20 | | 44.40 |
| L5 | 4.30 | | 4.70 |
| L6 | 24.30 | | 24.70 |
| L7 | 14.60 | | 15 |
| N | 1.80 | | 2.20 |
| R | 3.80 | | 4.20 |
| Dia | 3.40 | | 3.80 |



TO-247 mechanical data

| Dim. | mm. | | |
|----------|-------|-------|-------|
| | Min. | Typ | Max. |
| A | 4.85 | | 5.15 |
| A1 | 2.20 | | 2.60 |
| b | 1.0 | | 1.40 |
| b1 | 2.0 | | 2.40 |
| b2 | 3.0 | | 3.40 |
| c | 0.40 | | 0.80 |
| D | 19.85 | | 20.15 |
| E | 15.45 | | 15.75 |
| e | | 5.45 | |
| L | 14.20 | | 14.80 |
| L1 | 3.70 | | 4.30 |
| L2 | | 18.50 | |
| ϕP | 3.55 | | 3.65 |
| ϕR | 4.50 | | 5.50 |
| S | | 5.50 | |



5 Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|---|
| 15-Apr-2009 | 1 | First release. |
| 02-Aug-2010 | 2 | Document status promoted from preliminary data to datasheet. Inserted Section 2.1: Electrical characteristics (curves) . |

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